

Search Notes

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Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

SHEN ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
426	656, 634, 590, 598	1/7/2006	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Search	1/7/2006	AW